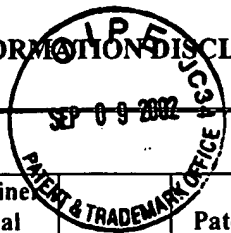


**EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP §609.  
Draw line through citation if not in conformance and not considered.  
Include copy of this form with next communication to Applicant.

<b>FORM PTO-1449</b> <b>INFORMATION DISCLOSURE CITATION</b>				Attorney Docket: 1232-4837		Serial No.: 10/099,717	
				Applicant: KOSHIMIZU, et al.		<b>MAILED</b> <b>SEP 18 2002</b>	
				Filing Date: March 13, 2002		Group Art Unit: <del>2622</del> 2627	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial	Patent Number	Issue Date	Name	Class	Sub-Class	Filing Date	
<i>CFL</i>	AA 5,359,691	10/25/94	Tai et al.	385	146	4/19/93	
<i>CFL</i>	AB 5,667,289	9/16/97	Akahane et al.	362	31	4/7/92	
<i>CFL</i>	AC 5,695,269	12/9/97	Lippmann et al.	362	27	1/29/96	
<b>FOREIGN PATENT DOCUMENTS</b>							
Examiner Initial	Patent Number	Issue Date	Country	Class	Sub-Class	Translation	
<i>CFL</i>	AD WO 98/34397	8/6/98	WO	—	—		
<i>CFL</i>	AE EP 0 510 421 A2	10/28/92	Europe	—	—		
<i>CFL</i>	AF EP 1 076 205 A1	2/14/01	Europe	—	—		
<i>CFL</i>	AG 08307608	11/22/96	Japan	—	—	Abstract Only	
<i>CFL</i>	AF 10126578	5/15/98	Japan	—	—	Abstract Only	
<b>OTHER DOCUMENTS (Including Author, Title, Date, etc.)</b>							
<i>CFL</i>	AG	U.S. Patent Application Publication, <i>Koshimizu</i> , Pub. No.: US 2001/0030278 A1; Pub. Date: Oct. 18, 2001					
<i>CFL</i>	AH	European Search Report dated July 1, 2002					
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
	AO						
	AP						
Examiner <i>Chenfan Lee</i>				Date Considered <i>10-1-05</i>			
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